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# EEE105

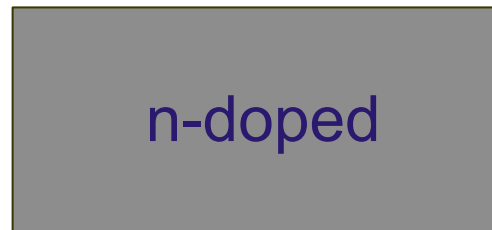
## “Electronic Devices”

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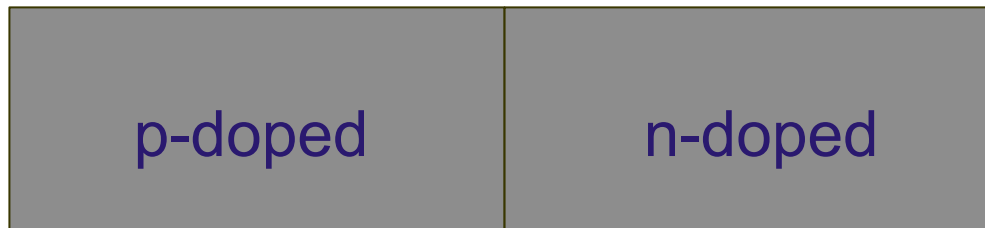
# Lecture 12

- p-n Junction
  - Putting two blocks of doped material together...
- Built in Potential
  - Derivation
- Band Structure p-n junction

# Two Blocks



2 isolated n and p  
doped blocks  
(constant doping)  
of semiconductor



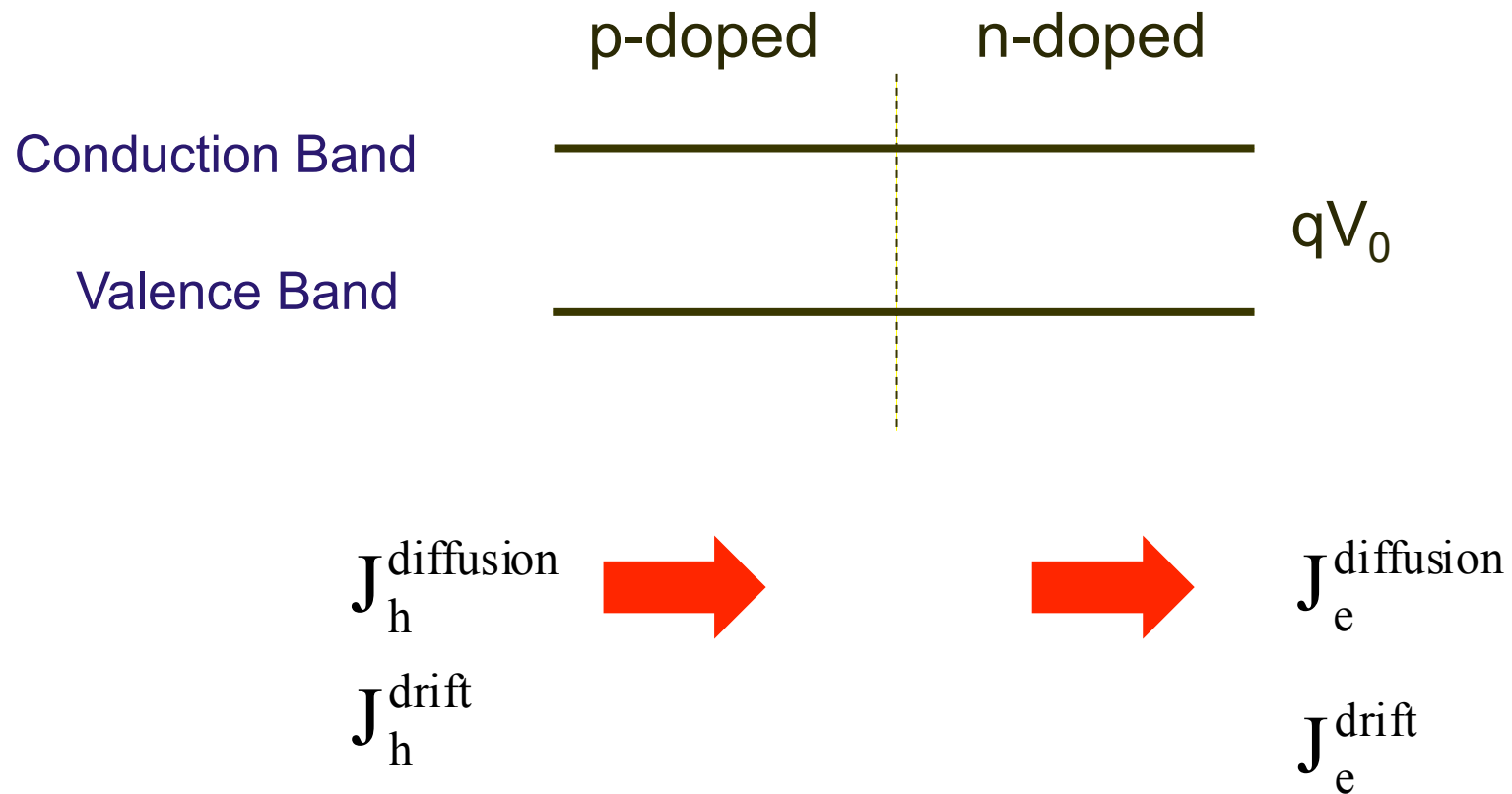
Bring them together –  
now have a non-  
uniform carrier  
concentration at the  
junction of the two

What happens?

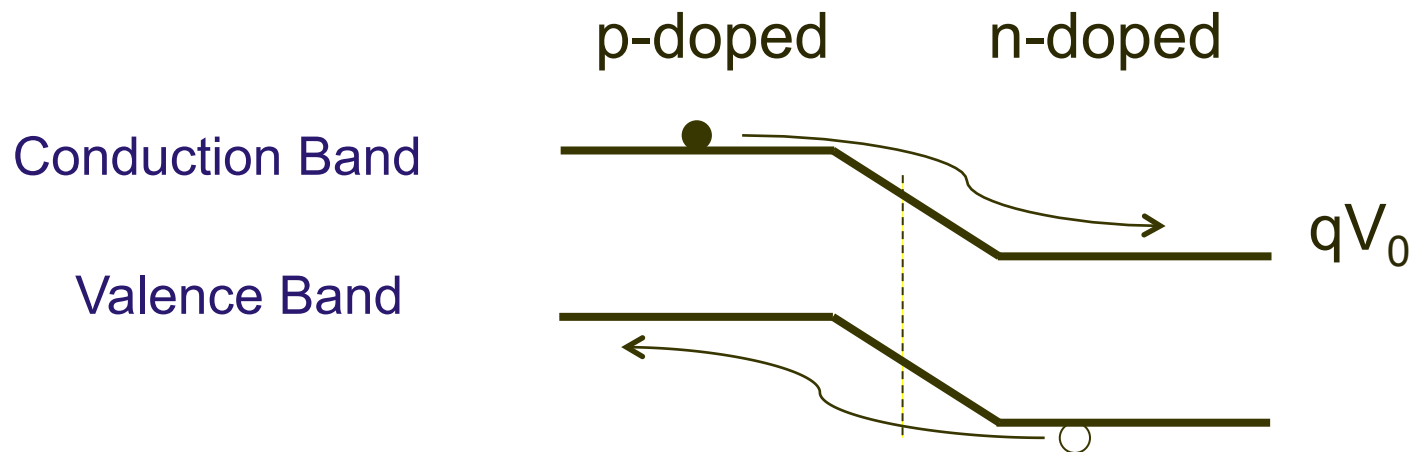
# J must be zero....

- An electric field must be generated to create a drift current which is equal and opposite to the diffusion current
- This electric field will appear to be a built-in potential within the junction,  $V_0$
- Here we will try to calculate the magnitude of  $V_0$  and see what factors influence it....

# No Internal Field -



# Origin of Drift Current

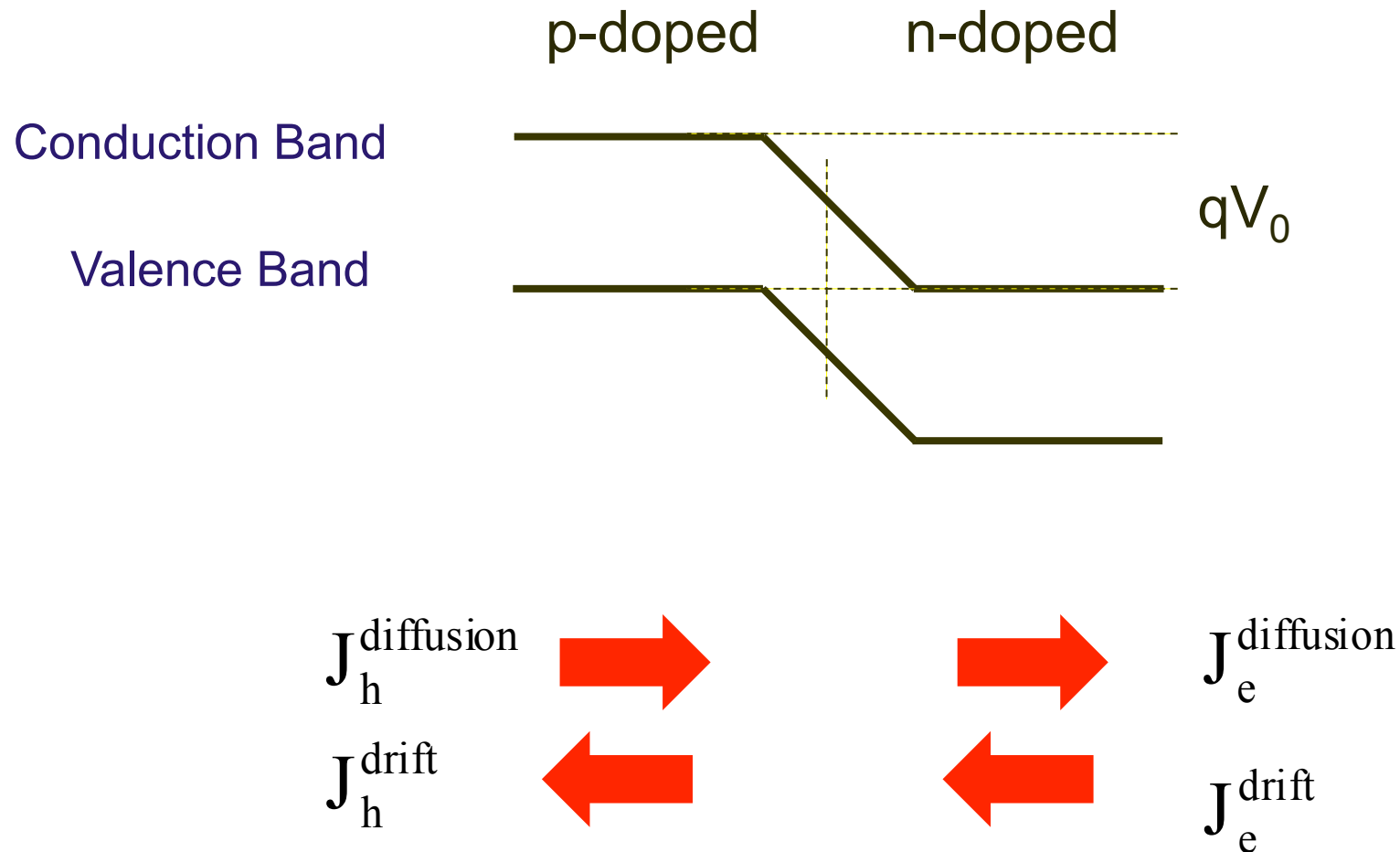


Minority carriers may “wander” into the region of electric field and be “swept away” contributing to drift current

Thermally generated carriers within diffusion length of E-field

$$L_{e,h} = (D_{e,h} \tau_{e,h})^{1/2}$$

# Just right – Balance – $J=0$





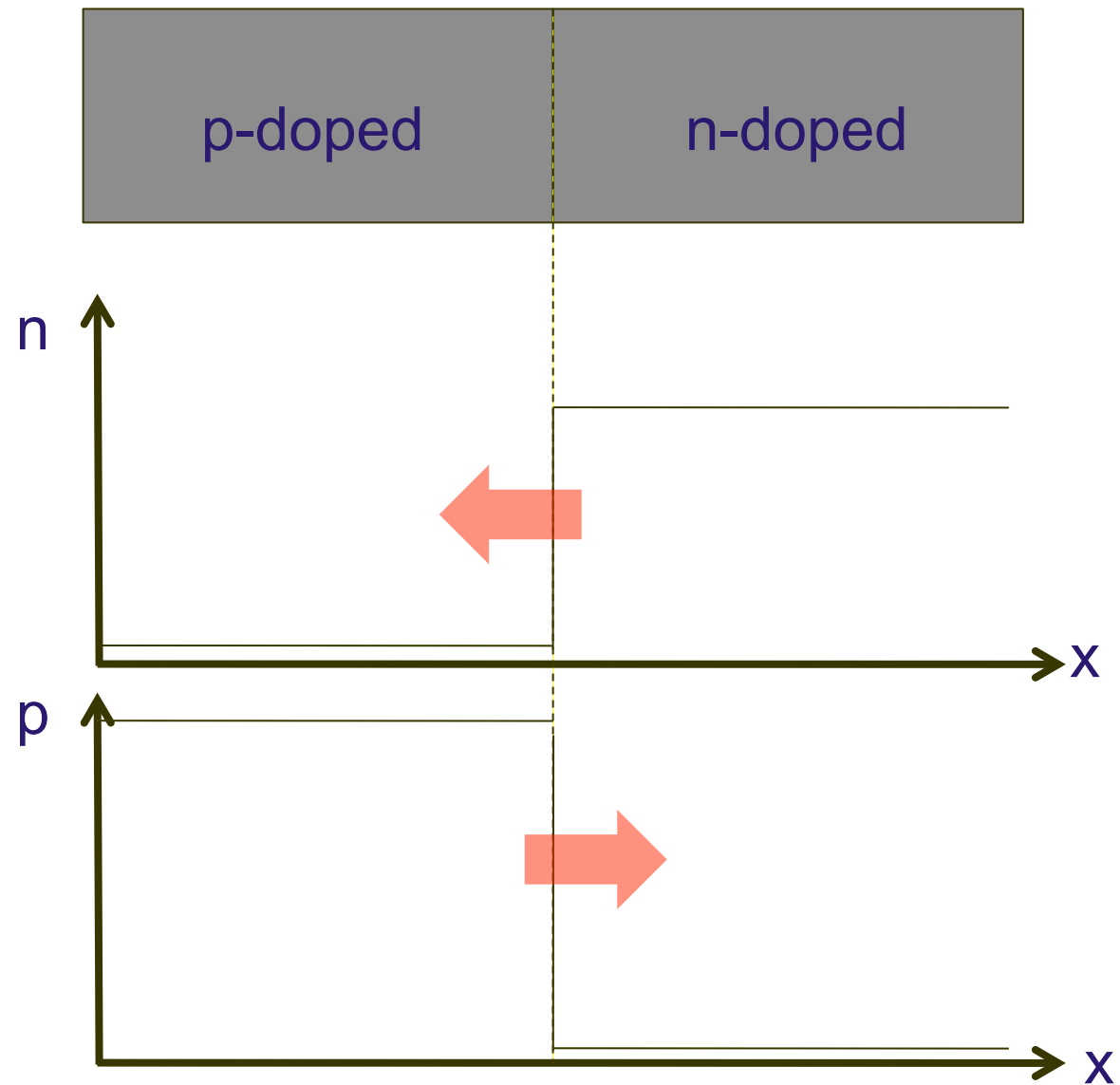
# Carriers

( $t=0$  after connection)

Holes diffuse into n-material where they are minority carriers and recombine with electrons

The holes leave behind ionized (-ve) acceptors in p-region

*Depletion* of free carriers at junction





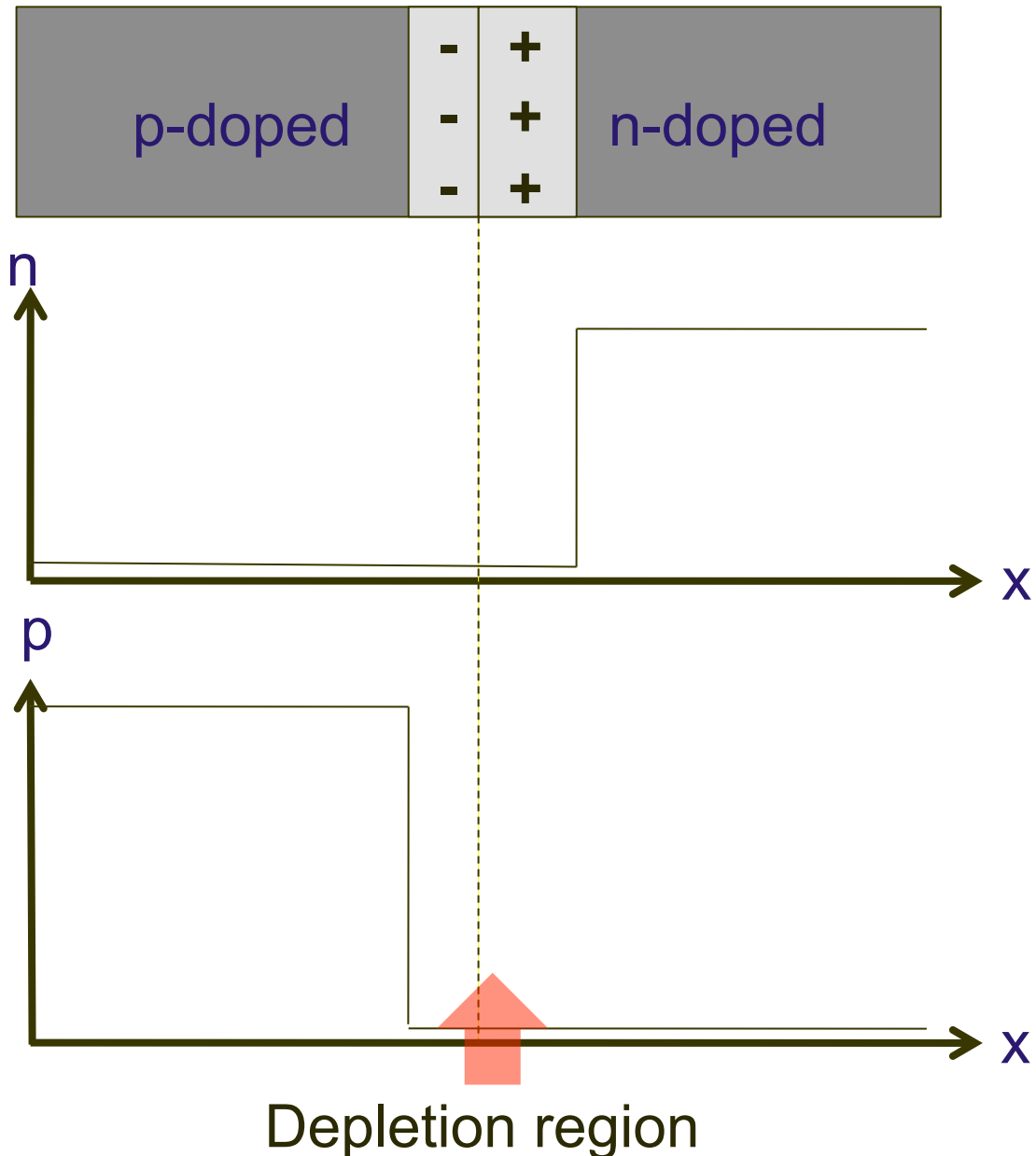


# Carriers

Have electron diffusion  
right to left (current left to  
right)

Have hole diffusion left to  
right (current left to right)

At equilibrium there must  
be no net current so an E-  
field is generated – Gives  
potential difference  $V_0$   
between n and p regions



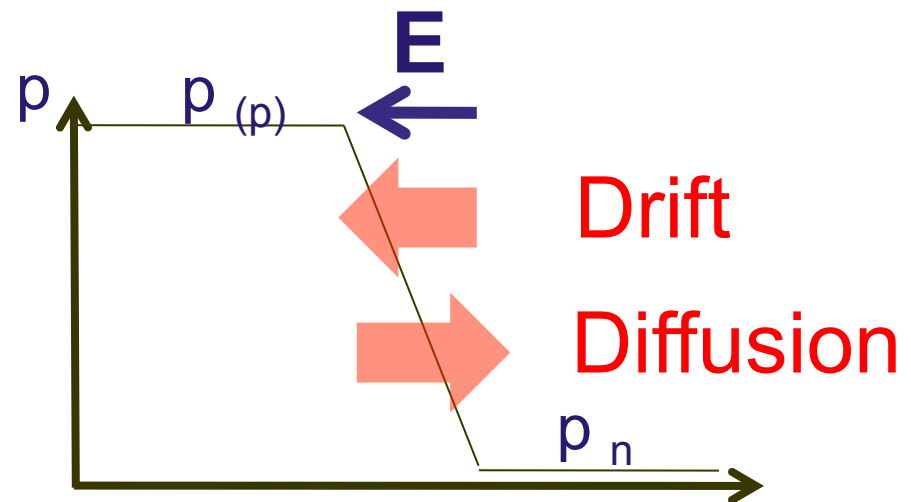
# $V_0$ - Consider holes

From discussion on drift and diffusion

$$J_h^{\text{total}}(x) = J_h^{\text{drift}} + J_h^{\text{diffusion}} = q\mu_h E_x p - qD_h \frac{dp}{dx} = 0$$

Rearranging

$$E_x = \frac{D_h}{\mu_h p} \cdot \frac{dp}{dx}$$



# Continued..

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Recall Einstein relationship

$$D_h = \frac{k_B T}{q} \cdot \mu_h$$

Gives  $E_x = \frac{k_B T}{q} \cdot \frac{1}{p} \cdot \frac{dp}{dx}$

Remember that

$$V = -\int E \cdot dx$$

Combining these gives  $V_0 = -\frac{k_B T}{q} \int_{p(p)}^{p_n} \frac{dp}{p}$

Integration yields  $V_0 = \frac{k_B T}{q} \ln\left(\frac{p_{(p)}}{p_n}\right)$

n.b. Same analysis gives similar for electrons  $V_0 = \frac{k_B T}{q} \ln\left(\frac{n_{(n)}}{n_p}\right)$

# Continued (2)..

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In terms of minority carrier density isn't helpful....

Remember  $n_i^2 = n_p p_p$

Gives  $V_0 = \frac{k_B T}{q} \ln \left( \frac{p_{(p)} n_{(n)}}{n_i^2} \right)$

All are known, or can be calculated

T= Temperature

$p_{(p)}$  = acceptor doping density

$n_{(n)}$  = donor doping density

$n_i$  = intrinsic carrier density

$$n_i = C T^{3/2} \exp \left( - \frac{E_g}{2K_B T} \right)$$



# Continued (3)..

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What is dominant ?

$$V_0 = \frac{k_B T}{q} \left[ \ln(p_{(p)} n_{(n)}) - \ln(n_i^2) \right]$$

Substituting for  $n_i$

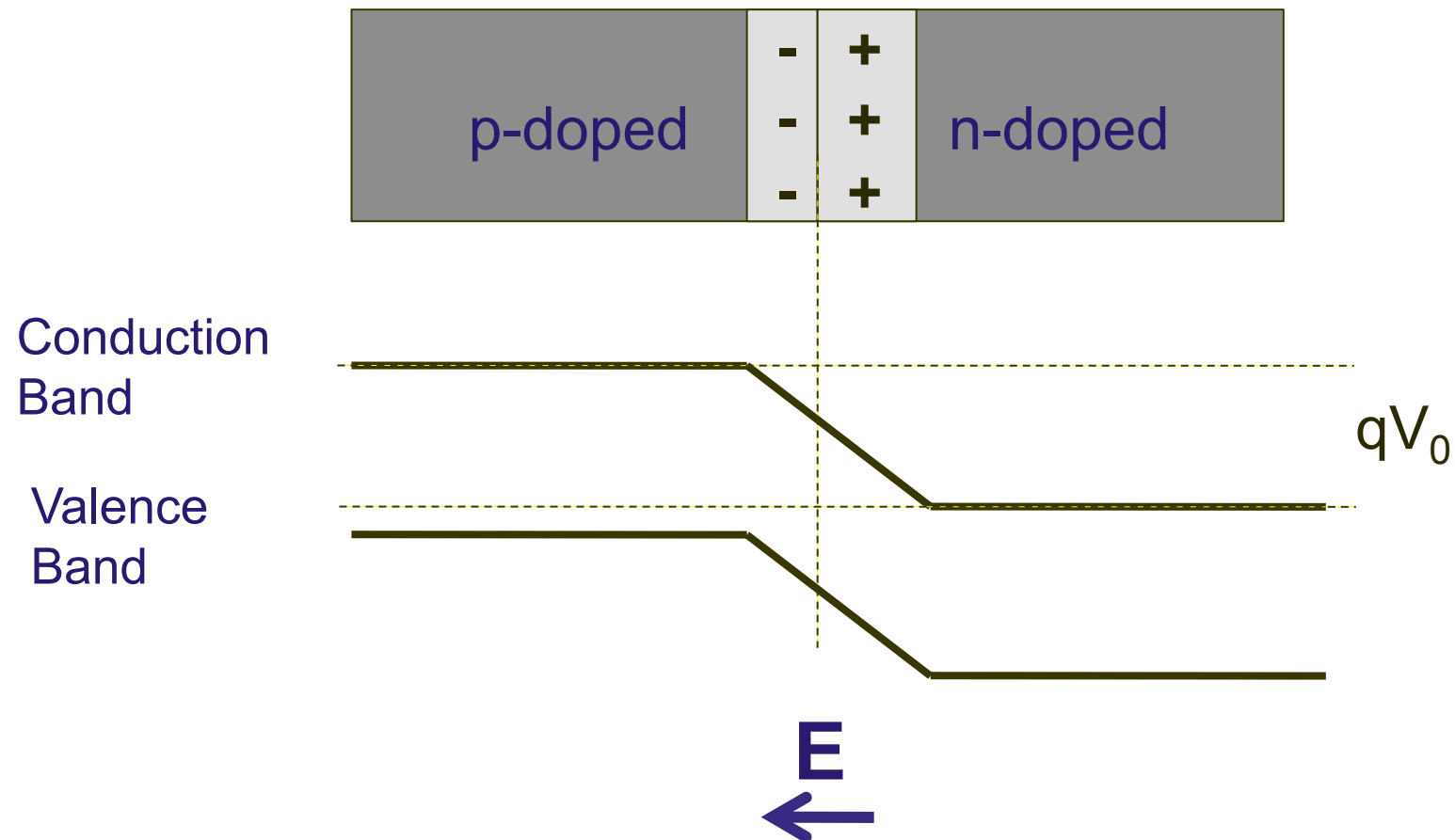
$$V_0 = \frac{k_B T}{q} \left[ \ln(p_{(p)} n_{(n)}) - \ln(CT^{3/2})^2 + \frac{E_g}{k_B T} \right]$$

$$V_0 = \underbrace{\frac{k_B T}{q} \left[ \ln(p_{(p)} n_{(n)}) - \ln(CT^{3/2})^2 \right]}_{\text{Small compared to } E_g} + \frac{E_g}{q}$$

Small compared to  $E_g$



# Band Structure



# Summary

- In a p-n junction electrons and holes will diffuse across the junction and recombine as minority carriers
- The acceptor and donor ions are left behind and cannot move
- In equilibrium the diffusion and drift currents must give no net current
- An E-field is produced to ensure this
- There is a built in voltage in the junction
  - This is an internal barrier to current flow
  - We cannot measure this at the terminals

## Summary (2)

- The built in voltage is close to the band-gap
- The temperature dependence of the built in voltage comes from a temperature dependence of the band-gap
- The position of the E-fields with relation to the junction of n and p materials is dependant upon the relative doping concentrations